

Notice of References Cited	Application/Control No. 10/712,248	Applicant(s)/Patent Under Reexamination FREYDINA ET AL.	
	Examiner Betsey M. Hoey	Art Unit 1724	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,197,189	03-2001	Schwartz et al.	210/192
	B	US-6,103,125	08-2000	Kuepper, Theodore A.	210/637
	C	US-6,190,553	02-2001	Lee, Sang Eul	210/602
	D	US-6,375,812	04-2002	Leonida, Andrei	204/269
	E	US-6,783,666	08-2004	Takeda et al.	210/96.1
	F	US-6,648,307	11-2003	Nelson et al.	261/121.1
	G	US-6,146,524	11-2000	Story, Craig W.	210/199
	H	US-6,274,019	08-2001	Kuwata, Masahiro	204/632
	I	US-RE36,972	11-2000	Baker et al.	422/186.07
	J	US-6,808,608	10-2004	Srinivasan et al.	204/533
	K	US-6,187,154	02-2001	Yamaguchi et al.	204/228.6
	L	US-3,630,378	12-1971	Bauman, William C.	210/157
	M	US-6,627,073	09-2003	Hirota et al.	210/169

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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